

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: BRUNNER ET AL - 1

FILING DATE: Oct. 22, 1999 GROUP: 1765

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	O I P E					
	AB	DEC 23 1999					
	AC	JC16					
	AD	PATENT & TRADEMARK OFFICE					
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
C.B.	AL	0701275	03/13/96	EUROPE	401	21/306		
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

C.B.	AR	Abstract for JP 4-26120 F
C.B.	AS	Document P 165 Fig. 1 L 1993: 45 13.8.93 for Proceedings of the Second Int. Symp. on Cleaning Tech. in Semiconductor Device Manufacturing, Electrochem. Soc., 1992 pp. 18-25
C.B.	AT	M. Meunis et al., Solid State Technology, July 95, p 109

EXAMINER *Carlo A. Baum*

DATE CONSIDERED

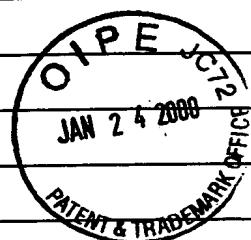
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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO.: ST 980	SERIAL NO.: 09/425,694
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
C.B.	AA	5 803 980	09/08/98	Das et al.			
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	MAIL ROOM
C.B.	AL	0731 495	09/11/96	Europe			NO	2000
C.B.	AM	0844 650	05/27/98	Europe			NO	2000
C.B.	AN	0731 498	09/11/96	Europe			NO	2000
C.B.	AO	0859 404	08/19/98	Europe			NO	2000
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

CB.	AR	/	Patent Abstracts of Japan, vol. 1996, no. 06, June 28, 1996 & JP 08 03 18374 (Mitsubishi Materials Silicon Corp.)
		/	Others: 01, February 2, 1996
CB	AS	/	Meunis M et al: "The IMEC Clean: A New Concept For
		/	Particle and Metal Removal On Si Surfaces", Solid State Technology, US, Cowan Publ. Corp. Washington
CB	AT		

EXAMINER

Charlotte A Brown

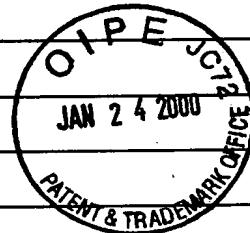
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

CB	AR	vol. 38, no. 7, 1995, p. 109-110, 112, 114
		XP 000523398, ISSN: 0038-111X, p. 10,
CB	AS	1.5 - 44
		The English Derwent Abstract 1996-404246 [417]
	AT	comes to EP 0731495 A2 is enclosed

EXAMINER <u>Phillip A Brown</u>	DATE CONSIDERED <u>3-23-00</u>
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